

Is Now Part of



ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at www.onsemi.com

Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (_), the underscore (_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.onsemi.com. Please email any questions regarding the system integration to Fairchild guestions@onsemi.com.

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officer



September 2015

FDMC8360LET40

N-Channel Shielded Gate Power Trench[®] MOSFET 40 V, 141 A, 2.1 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 2.1 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 27 \text{ A}$
- Max $r_{DS(on)} = 3.1 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 22 \text{ A}$
- lacktriangle High Performance Technology for Extremely Low $r_{DS(on)}$
- Termination is Lead-free
- 100% UIL Tested
- RoHS Compliant

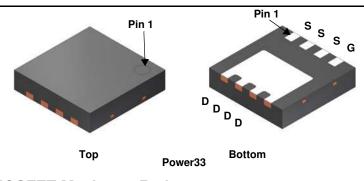
General Description

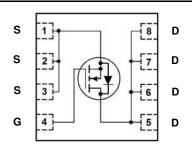
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates shielded gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance.

Application

■ DC-DC Conversion







MOSFET Maximum Ratings $T_A = 25$ °C unless otherwise noted.

Symbol	Parameter			Ratings	Units	
V _{DS}	Drain to Source \	/oltage			40	V
V_{GS}	Gate to Source V	oltage			±20	V
	Drain Current	-Continuous	T _C = 25 °C	(Note 5)	141	
		-Continuous	T _C = 100 °C	(Note 5)	100	A
ID		-Continuous	T _A = 25 °C	(Note 1a)	27	A
		-Pulsed		(Note 4)	658	
E _{AS}	Single Pulse Ava	lanche Energy		(Note 3)	253	mJ
В	Power Dissipation	n	T _C = 25 °C		75	W
P_{D}	Power Dissipation	n	$T_A = 25 ^{\circ}C$ (Note 1a)	2.8		
T _J , T _{STG}	Operating and St	orage Junction Tempera	ture Range		-55 to +175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	(Note 1)	2.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	53	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC8360LET	FDMC8360LET40	Power33	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Chara	acteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	40			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		20		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 32 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.0	1.7	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-6		mV/°C
	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 27 \text{ A}$		1.4	2.1	
r _{DS(on)}		$V_{GS} = 4.5 \text{ V}, I_D = 22 \text{ A}$		2.1	3.1	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 27 \text{ A}, T_J = 150 \text{ °C}$		2.3	3.5	1
9 _{FS}	Forward Transconductance	$V_{DD} = 5 \text{ V}, \ I_D = 27 \text{ A}$		138		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 20 V V 0 V		3785	5300	pF
C _{oss}	Output Capacitance	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$		1220	1710	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 101112		57	80	pF
R _a	Gate Resistance		0.1	0.8	1.6	Ω

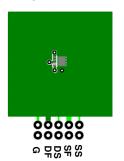
Switching Characteristics

t _{d(on)}	Turn-On Delay Time		14	26	ns
t _r	Rise Time	V _{DD} = 20 V, I _D = 27 A,	8	16	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	35	57	ns
t _f	Fall Time		7	14	ns
$Q_{g(TOT)}$	Total Gate Charge	V _{GS} = 0 V to 10 V	57	80	nC
$Q_{g(TOT)}$	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $V_{DD} = 20 \text{ V}$,	27	38	nC
Q_{gs}	Gate to Source Charge	I _D = 27 A	9.9		nC
Q_{gd}	Gate to Drain "Miller" Charge		8.1		nC

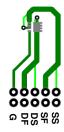
Drain-Source Diode Characteristics

V_{SD}	ISource to Drain Dioge Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 27 \text{ A}$ (Note 2)	0.8	1.3	V
		$V_{GS} = 0 \text{ V}, I_S = 1.9 \text{ A}$ (I	Note 2)	0.7	1.2	V
t _{rr}	Reverse Recovery Time	I _F = 27 A, di/dt = 100 A/μs		47	76	ns
Q _{rr}	Reverse Recovery Charge	IF = 27 A, α//αι = 100 A/μS		30	48	nC

^{1.} R_{BJA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.



a) 53°C/W when mounted on a 1 in² pad of 2 oz copper



b) 125°C/W when mounted on a minimum pad

^{2.} Pulse Test: Pulse Width < 300 $\mu\text{s},$ Duty cycle < 2.0%.

^{3.} E_{AS} of 253 mJ is based on starting $T_J = 25$ °C, L = 3 mH, $I_{AS} = 13$ A, $V_{DD} = 40$ V, $V_{GS} = 10$ V. 100% test at L = 0.1 mH, $I_{AS} = 42$ A.

^{4.} Pulsed Id please refer to Fig 11 SOA graph for more details.

^{5.} Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

Typical Characteristics T_J = 25°C unless otherwise noted.

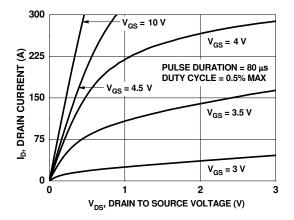


Figure 1. On Region Characteristics

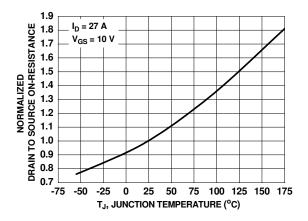


Figure 3. Normalized On Resistance vs. Junction Temperature

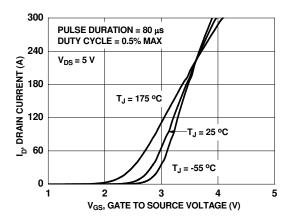


Figure 5. Transfer Characteristics

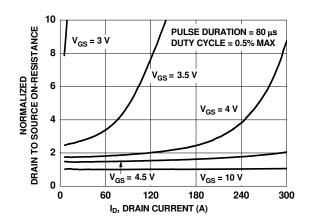


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

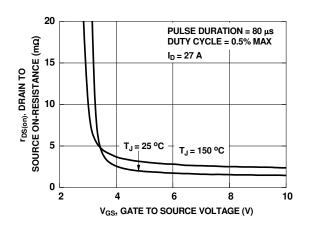


Figure 4. On-Resistance vs. Gate to Source Voltage

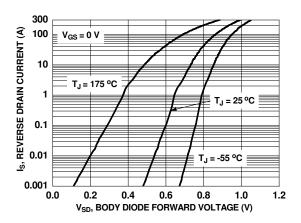


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted.

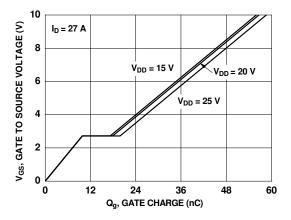


Figure 7. Gate Charge Characteristics

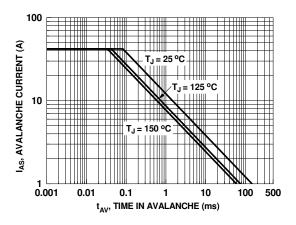


Figure 9. Unclamped Inductive Switching Capability

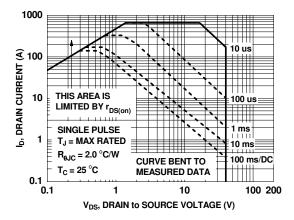


Figure 11. Forward Bias Safe Operating Area

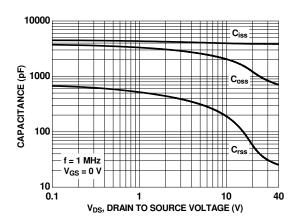


Figure 8. Capacitance vs. Drain to Source Voltage

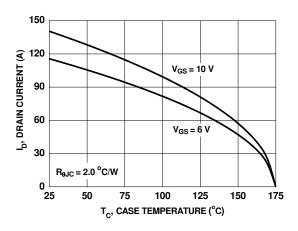


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

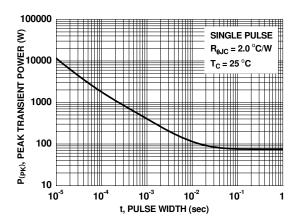


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted.

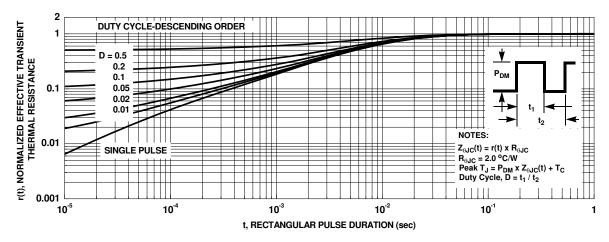
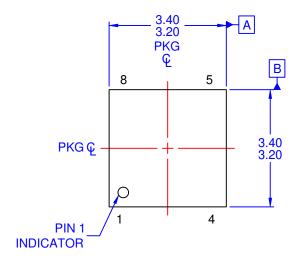
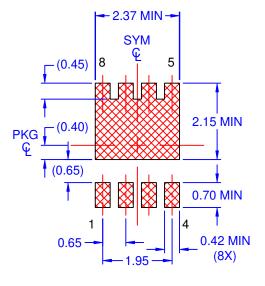
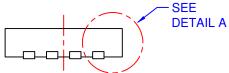


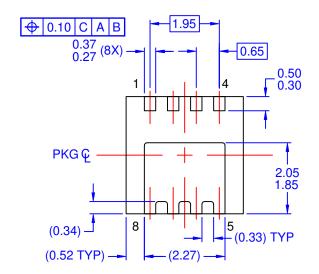
Figure 13. Junction-to-Case Transient Thermal Response Curve





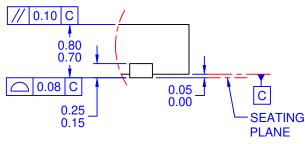


LAND PATTERN RECOMMENDATION



NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. BA, DATED OCTOBER 2002.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- E) DRAWING FILE NAME: PQFN08HREV1



DETAIL A

ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hol

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Japan Customer Focus Center Phone: 81–3–5817–1050 ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative